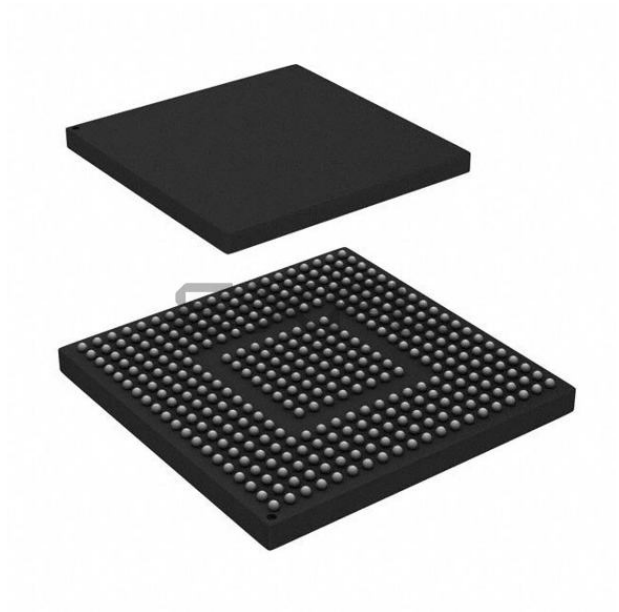

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	ARM® Cortex®-A5 + Cortex®-M4
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	400MHz, 133MHz
Co-Processors/DSP	Multimedia; NEON™ MPE
RAM Controllers	LPDDR2, DDR3, DRAM
Graphics Acceleration	Yes
Display & Interface Controllers	DCU, GPU, LCD, VideoADC, VIU
Ethernet	10/100Mbps (2)
SATA	-
USB	USB 2.0 OTG + PHY (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 85°C (TA)
Security Features	ARM TZ, Hashing, RNG, RTC, RTIC, Secure JTAG, SNVS, TZ ASC, TZ WDOG
Package / Case	364-LFBGA
Supplier Device Package	364-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/svf522r3k1cmk4

3 Terminology and guidelines

3.1 Definition: Operating requirement

An *operating requirement* is a specified value or range of values for a technical characteristic that you must guarantee during operation to avoid incorrect operation and possibly decreasing the useful life of the chip.

3.1.1 Example

This is an example of an operating requirement:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	0.9	1.1	V

3.2 Definition: Operating behavior

Unless otherwise specified, an *operating behavior* is a specified value or range of values for a technical characteristic that are guaranteed during operation if you meet the operating requirements and any other specified conditions.

3.2.1 Example

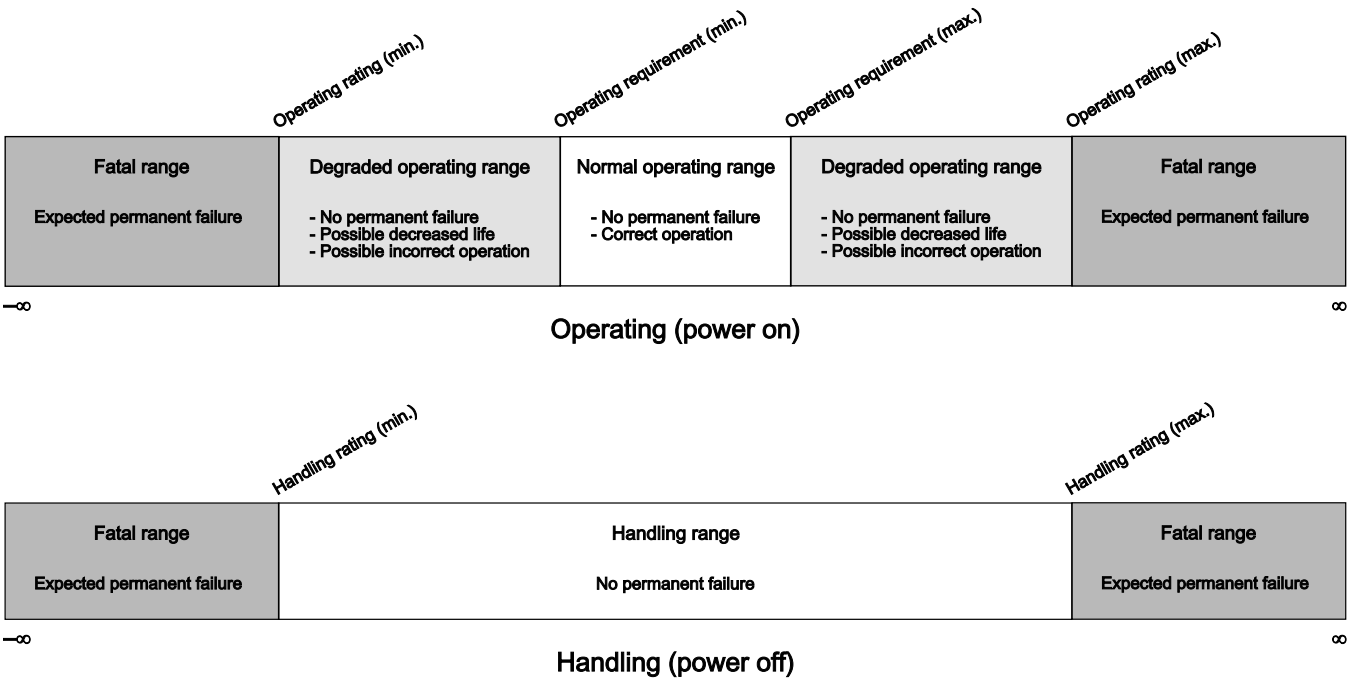
This is an example of an operating behavior:

Symbol	Description	Min.	Max.	Unit
I_{WP}	Digital I/O weak pullup/ pulldown current	10	130	µA

3.3 Definition: Attribute

An *attribute* is a specified value or range of values for a technical characteristic that are guaranteed, regardless of whether you meet the operating requirements.

3.6 Relationship between ratings and operating requirements



3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

4 Handling ratings

4.1 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V_{HBM}	Electrostatic discharge voltage, human body model	-2000	2000	V	1
V_{CDM}	Electrostatic discharge voltage, charged-device model	-500	500	V	2
I_{LAT}	Latch-up Current at ambient temperature of 85 °C	-100	100	mA	

1. Determined according to the AEC spec AEC-Q100-002 for HBM
2. Determined according to AEC spec AEC-Q100-011

4.2 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T_{STG}	Storage temperature	–55	150	°C	1
T_{SDR}	Solder temperature, lead-free	—	260	°C	2
	Solder temperature, leaded	—	245		

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

Table 8. General guidelines for selection of NPN ballast

Symbol	Parameters	Value	Unit	Comments
Hfe	Minimum DC current gain (Beta)	42.5		As BCTRL pin can not drive more than 20mA Minimum value of beta for a collector current of 0.85A comes out to be 42.5.
PD (Junction to ambient)	Minimum power dissipation @ TA=85 °C	2.04	W	Assuming 0.85A collector current with Collector voltage of Ballast 3.6V(max) we get VCE= 3.6V-1.2V=2.4V So power dissipated is 2.4V*0.85A=2.04W . This should be met for junction to ambient power dissipation spec of ballast
IcmaxDC peak	Maximum peak DC collector current	0.85	A	1.2A and above capacity device preferable
VBE	Maximum voltage that BCTRL pin can drive	1.25V for 0.85A @ 85 °C	V	For a VDDREG of 3.0 V (min.), BCTRL pin can drive voltage up to VDDREG - 0.5 V = 2.5 V. Since emitter of ballast is fixed at 1.25 V (max) if chosen ballast can supply 0.85 A collector current @ 85 °C with a base-to-emitter voltage of 1.25 V or lower, it is suitable for application.
Ft	Unity current gain Frequency of Ballast	50	MHz	

Reducing the collector-to-emitter voltage drop lowers the ballast transistor heat dissipation. This can be implemented in two ways:

1. By introducing series resistor or diode(s) between the collector and VDDREG (placed far enough from the transistor for proper cooling)
2. By connecting the collector to a separate lower-voltage supply

In both of the above cases the transistor has to stay away from the deep saturation region; otherwise, due to significant Hfe degradation, its base current exceeds the BCTRL output maximum value.

In general, the transistor must be selected such that its Vce saturation voltage is lower than the expected minimum Collector-Emitter voltage, and at the same time, the base current is less than 20 mA for the maximum expected collector current. More information can be found in collateral documentation at http://www.freescale.com

2. The Max numbers represent the single worst case value taken from a matrix lot of parts across normal process variation at maximum temperature.
3. CA5, CM4 cores halted
4. 24MHz operation, PLL Bypass
5. 32 kHz /128 kHz operation, PLL Off
6. Lowest power mode with all power retained, RAM retention and LVD protection.
7. Standby Mode. 64K RAM retention. I/O states held. ADCs/DACs optionally power-gated. RTC functional. Wakeup from interrupts. Fast IRC enabled.
8. Standby Mode 16K RAM retention. I/O states held. ADCs/DACs optionally power-gated. RTC functional. Wakeup from interrupts. Fast IRC enabled.
9. All supplies OFF, SRTC, 32kXOSC ON, tampers and monitors ON. 128k IRC optionally ON.

6.2.5 USB PHY current consumption

6.2.5.1 Power Down Mode

Everything powered down, including the VBUS valid detectors, typ condition.

Table 16. USB PHY Current Consumption in Normal Mode

	USBx_VBUS (3.0V) Avg	VDD33_LDOIN (2.5V) Avg	VDD33_LDOIN (1.1V) Avg
Current	5.1 µA	1.7 µA	<0.5 µA

NOTE

The currents on the 2.5 voltage regulator and 3.0 voltage regulator were identified to be the voltage divider circuits in the USB-specific level shifters.

6.2.6 EMC radiated emissions operating behaviors

Table 17. EMC radiated emissions operating behaviors

Symbol	Condition[1]	Clocks	Frequency band [2]	Level (Typ)[3]	Unit
V_{EME}	Device Configuration, test conditions and EM testing per standard IEC 61967-2; Supply voltages: VDD= 5.0 V VDD33 = 3.3 V VDD15 = 1.5 V VDD12 = 1.2 V Temp = 25°C	FCPU = 396 MHz FBUS = 66 MHz External Crystal = 24 MHz	150 KHz – 50 MHz	22	dBµV
			50 MHz – 150 MHz	24	
			150 MHz – 500 MHz	25	
			500–1000	20	
			IEC level[4]	K	—

1. Measurements were made per IEC 61967-2 while the device was running basic application code.
2. Measurements were performed on the BGA364 version of the device

USB bus during standby. This supply can be turned-off during standby in applications that cannot tolerate the standby current and do not monitor the USB bus.

8.2 Power supply

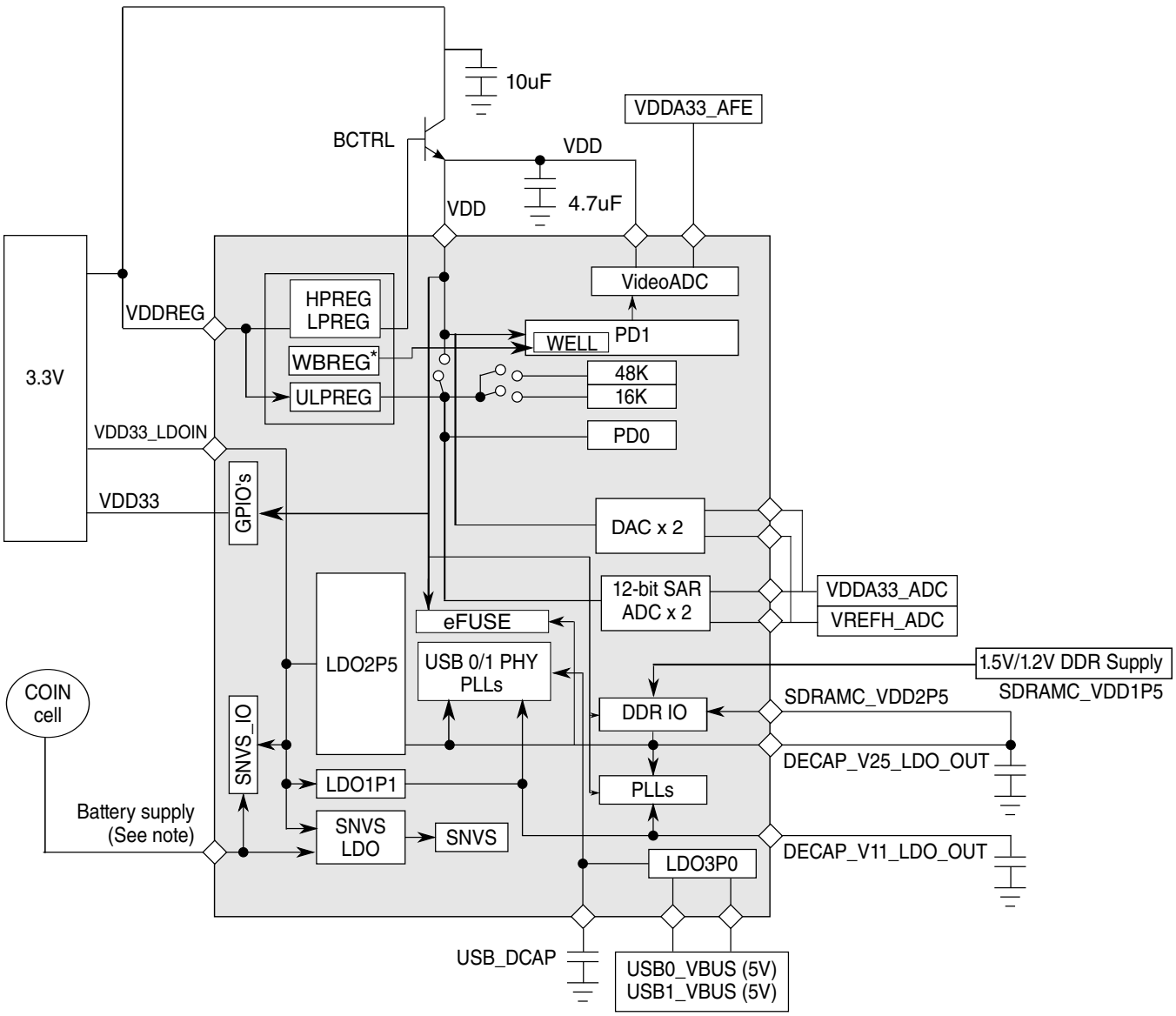


Figure 4. Power supply

NOTE

VBAT is the backup battery supply. If not required, then VBAT should be tied to VDDREG.

9.2.3 LCD driver electrical characteristics

This section provides LCD driver electrical specification at V_{DD33} = 3.3 V ± 10%.

Table 39. LCD driver specifications

Symbol	Parameter	Min	Typical	Max	Unit
VLCD	Voltage on VLCD (LCD supply) pin with respect to VSS	0		VDD33 + 0.3	V
$Z_{BP/FP}$	LCD output impedance (BP[n-1:0],FP[m-1:0]) for output levels VDDE, VSS	_	_	5.0	KΩ
$I_{BP/FP}$	LCD output current (BP[n-1:0],FP[m-1:0]) for outputs charge/discharge voltage levels VDDE2/3, VDDE1/2, VDDE/3)[1]	_	25	_	µA

1. With PWR=10, BSTEN=0, and BSTAO=0

9.3 Ethernet specifications

9.3.1 Ethernet Switching Specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface. All Ethernet signals use pad type pad_fsr. The timing specifications described i the section assume a pad slew rate setting of 11 and a load of 50 pF[2].

9.3.2 Receive and Transmit signal timing specifications

This section provides timing specs that meet the requirements for RMII interfaces for a range of transceiver devices.

Table 40. Receive signal timing for RMII interfaces

	Characteristic	RMII Mode		Unit
		Min	Max	
—	EXTAL frequency (RMII input clock RMII_CLK)	—	50	MHz
E3, E7	RMII_CLK pulse width high	35%	65%	RMII_CLK period

Table continues on the next page...

2. These timing parameters are specified assuming maximum operating frequency and the fastest pad slew rate setting (11). When operating this interface at lower frequencies, increase the slew rate by using the 10, 01, or 00 setting to increase edge rise and fall times, thus reducing EMI.

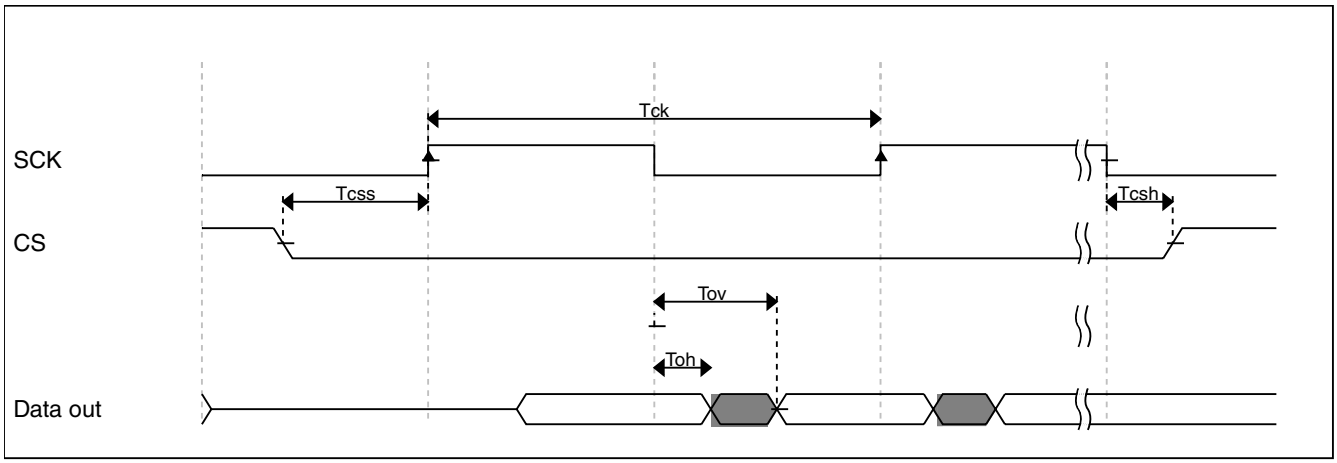


Figure 33. QuadSPI Output/Write timing (DDR mode)

Table 51. QuadSPI Output/Write timing (DDR mode)

Symbol	Parameter	Value		Unit
		Min	Max	
T_{ov}	Output Data Valid	—	3.2	ns
T_{oh}	Output Data Hold	0	—	ns
T_{ck}	SCK clock period	-	45	MHz
T_{css}	Chip select output setup time	3	-	Clk(sck)
T_{csh}	Chip select output hold time	3	-	Clk(sck)

9.5.2 NFC specifications

The NAND flash controller (NFC) implements the interface to standard NAND flash memory devices. This section describes the timing parameters of the NFC.

In the following table:

- T_H is the flash clock high time and
- T_L is flash clock low time,

which are defined as:

$T_{NFC} = T_H + T_L$

NOTE

Refer to the Reference Manual for further details on setting up the NFC clocks (CCM_CSCDR2[NFC_FRAC_DIV_EN + NFC_FRAC_DIV] and CCM_CSCDR3[NFC_PRE_DIV]).

Table 52. NFC specifications

Num	Description	Min.	Max.	Unit
t_{CLS}	NFC_CLE setup time	$2T_H + T_L - 1$	—	ns
t_{CLH}	NFC_CLE hold time	$T_H + T_L - 1$	—	ns
t_{CS}	$\overline{\text{NFC\_CEn}}$ setup time	$2T_H + T_L - 1$	—	ns
t_{CH}	$\overline{\text{NFC\_CEn}}$ hold time	$T_H + T_L$	—	ns
t_{WP}	$\overline{\text{NFC\_WP}}$ pulse width	$T_L - 1$	—	ns
t_{ALS}	NFC_ALE setup time	$2T_H + T_L$	—	ns
t_{ALH}	NFC_ALE hold time	$T_H + T_L$	—	ns
t_{DS}	Data setup time	$T_L - 1$	—	ns
t_{DH}	Data hold time	$T_H - 1$	—	ns
t_{WC}	Write cycle time	$T_H + T_L - 1$	—	ns
t_{WH}	$\overline{\text{NFC\_WE}}$ hold time	$T_H - 1$	—	ns
t_{RR}	Ready to $\overline{\text{NFC\_RE}}$ low	$4T_H + 3T_L + 90$	—	ns
t_{RP}	$\overline{\text{NFC\_RE}}$ pulse width	$T_L + 1$	—	ns
t_{RC}	Read cycle time	$T_L + T_H - 1$	—	ns
t_{REH}	$\overline{\text{NFC\_RE}}$ high hold time	$T_H - 1$	—	ns
t_{IS}	Data input setup time	11	—	ns

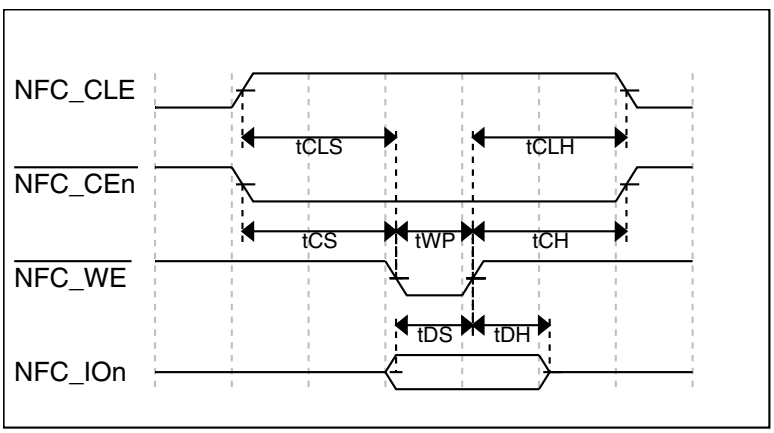


Figure 34. Command latch cycle timing

9.6 Communication interfaces

9.6.1 MediaLB (MLB) DC Characteristics

The section lists the MediaLB 3-pin interface electrical characteristics.

Table 60. MediaLB 3-Pin Interface Electrical DC Specifications

Parameter	Symbol	Test Conditions	Min	Max	Unit
Maximum input voltage	—	—	—	3.6	V
Low level input threshold	V_{IL}	—	—	0.7	V
High level input threshold	V_{IH}	See Note[1]	1.8	—	V
Low level output threshold	V_{OL}	I_{OL} = –6 mA	—	0.4	V
High level output threshold	V_{OH}	I_{OH} = –6 mA	2.0	—	V
Input leakage current	$_{IL}$	0 < Vin < VDD	—	±10	µA

1. Higher V_{IH} thresholds can be used; however, the risks associated with less noise margin in the system must be evaluated and assumed by the customer.

9.6.2 MediaLB (MLB) Controller AC Timing Electrical Specifications

This section describes the timing electrical information of the MediaLB module.

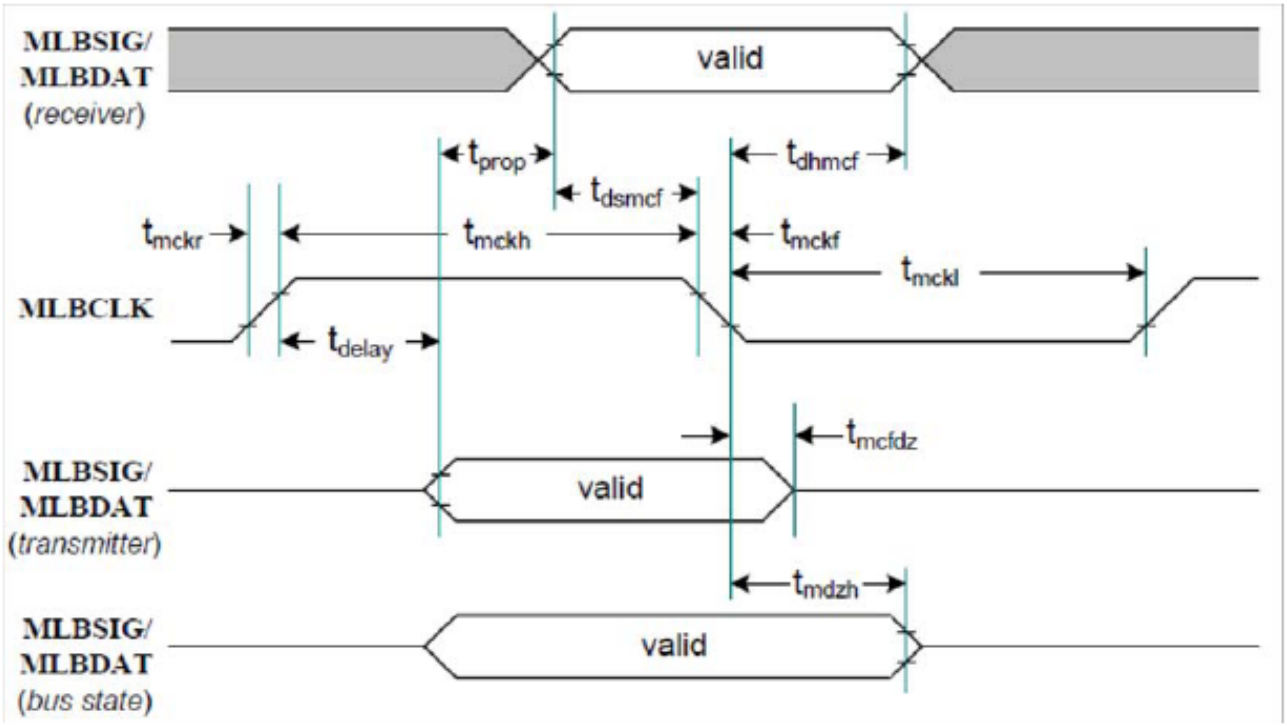


Figure 47. MediaLB 3-PinTiming

Ground = 0.0 V; Load Capacitance = 40 pF, input transition= 1 ns; MediaLB speed = 256/512 Fs; Fs = 48 kHz; all timing parameters specified from the valid voltage threshold as listed below; unless otherwise noted.

Table 61. MLB 256/512 Fs Timing Parameters

Parameter	Symbol	Min	Max	Unit	Comment
MLBCLK operating frequency	f_{mck}	11.264	25.6	MHz	256xFs at 44.0 kHz, 512xFs at 50.0 kHz
MLBCLK rise time	$t_{mck}r$	Refer Table 21		ns	$V_{IL\ to\ V_{IH}}$
MLBCLK fall time	$t_{mck}f$			ns	$V_{IH\ to\ V_{IL}}$
MLBCLK low time[1]	$t_{mck}l$	30, 14	—	ns	256xFs, 512xFs
MLBCLK high time	$t_{mck}h$	30, 14	—	ns	256xFs, 512xFs
MLBSIG/MLBDAT receiver input setup to MLBCLK falling	t_{dsmcf}	3	—	ns	—
MLBSIG/MLBDAT receiver input hold from MLBCLK low	t_{dhmcf}	2	—	ns	—
MLBSIG/MLBDAT output valid from MLBCLK low	t_{mcfdz}	0	16	ns	2
Bus output hold from MLBCLK low	t_{mdzh}	2	—	ns	—

1. MLBCLK low/high time includes the pluse width variation.

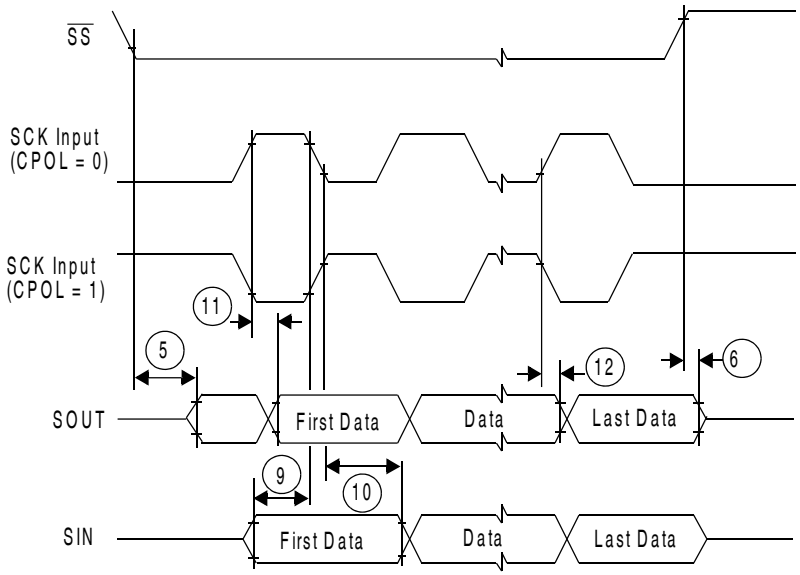


Figure 51. DSPI classic SPI timing slave, CPHA=1

9.6.4 I2C timing

Table 64. I2C input timing specifications — SCL and SDA[1]

No.	Parameter	Min.	Max.	Unit
1	Start condition hold time	2	—	PER_CLK Cycle[2]
2	Clock low time	8	—	PER_CLK Cycle
3	Bus free time between Start and Stop condition	4.7	—	µs
4	Data hold time	0.0	—	µs
5	Clock high time	4	—	PER_CLK Cycle
6	Data setup time	0.0	—	ns
7	Start condition setup time (for repeated start condition only)	2	—	PER_CLK Cycle
8	Stop condition setup time	2	—	PER_CLKCycle

1. I2C input timing is valid for Automotive and TTL inputs levels, hysteresis enabled, and an input edge rate no slower than 1 ns (10% – 90%).
2. PER_CLK is the IPG Clock which drive the I2C BIU and module clock inputs. Typically this is 83Mhz. See the Clocking Overview chapter in the device reference manual for more details.

Table 65. I2C output timing specifications — SCL and SDA[1234]

No.	Parameter	Min	Max	Unit
1	Start condition hold time	6	—	PER_CLK Cycle[5]

Table continues on the next page...

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
B14	162	PTB14		PTB14	CAN0_RX	I2C0_SCL		DCU0_ TCON8			DCU1_PCLK	
A14	161	PTB15		PTB15	CAN0_TX	I2C0_SDA		DCU0_ TCON9			VIU_PIX_ CLK	
C14	163	PTB16		PTB16	CAN1_RX	I2C1_SCL		DCU0_ TCON10				
A15	160	PTB17		PTB17	CAN1_TX	I2C1_SDA		DCU0_ TCON11				
B12	171	PTB18		PTB18	SPI0_PCS1	EXT_AUDIO_ MCLK				VIU_DATA9	CCM_OBS0	
C13	167	PTB19		PTB19	SPI0_PCS0					VIU_DATA10	CCM_OBS1	
A13	169	PTB20		PTB20	SPI0_SIN			LCD42		VIU_DATA11	CCM_OBS2	
E12	173	PTB21		PTB21	SPI0_SOUT			LCD43		VIU_DATA12	DCU1_PCLK	
D12	172	PTB22		PTB22	SPI0_SCK				VIU_FID			
V10	61	USB0_GND			USB0_GND							
T10	63	USB0_DP			USB0_DP							
T9	62	USB0_DM			USB0_DM							
W11	60	USB0_VBUS			USB0_VBUS							
Y10	59	USB_DCAP			USB_DCAP							
Y11	64	USB0_ VBUS_ DETECT			USB0_ VBUS_ DETECT							
Y9	—	USB1_GND			USB1_GND							
W9	—	USB1_DP			USB1_DP							
V9	—	USB1_DM			USB1_DM							
W10	—	USB1_VBUS			USB1_VBUS							
U9	—	USB1_ VBUS_ DETECT			USB1_ VBUS_ DETECT							
L4	8	PTC0		PTC0	RMII0_MDC/ MII0_MDC	FTM1CH0	SPI0_PCS3	ESAI_SCKT	SDHC0_CLK	VIU_DATA0	RCON18	
L5	9	PTC1		PTC1	RMII0_MDIO/ MII0_MDC	FTM1CH1	SPI0_PCS2	ESAI_FST	SDHC0_CMD	VIU_DATA1	RCON19	
M5	11	PTC2		PTC2	RMII0_CRS_ DV	SCI1_TX		ESAI_SDO0	SDHC0_ DAT0	VIU_DATA2	RCON20	
M3	12	PTC3		PTC3	RMII0_RXD1/ MII0_RXD[1]	SCI1_RX		ESAI_SDO1	SDHC0_ DAT1	VIU_DATA3	DCU0_R0	
L2	14	PTC4		PTC4	RMII0_RXD0/ MII0_RXD[0]	SCI1_RTS	SPI1_PCS1	ESAI_SDO2/ ESAI_SDI3	SDHC0_ DAT2	VIU_DATA4	DCU0_R1	
M1	15	PTC5		PTC5	RMII0_RXER/ MII0_RXER	SCI1_CTS	SPI1_PCS0	ESAI_SDO3/ ESAI_SDI2	SDHC0_ DAT3	VIU_DATA5	DCU0_G0	
N1	16	PTC6		PTC6	RMII0_TXD1/ MII0_TXD[1]		SPI1_SIN	ESAI_SDO5/ ESAI_SDI0	SDHC0_WP	VIU_DATA6	DCU0_G1	
N2	17	PTC7		PTC7	RMII0_TXD0/ MII0_TXD[0]		SPI1_SOUT	ESAI_SDO4/ ESAI_SDI1		VIU_DATA7	DCU0_B0	

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
C5	—	DDR_CS_b[0]			DDR_CS_b0							
D2	—	DDR_D[15]			DDR_D15							
H2	—	DDR_D[14]			DDR_D14							
C1	—	DDR_D[13]			DDR_D13							
G1	—	DDR_D[12]			DDR_D12							
E2	—	DDR_D[11]			DDR_D11							
H1	—	DDR_D[10]			DDR_D10							
D1	—	DDR_D[9]			DDR_D9							
J1	—	DDR_D[8]			DDR_D8							
G3	—	DDR_D[7]			DDR_D7							
C3	—	DDR_D[6]			DDR_D6							
J3	—	DDR_D[5]			DDR_D5							
F3	—	DDR_D[4]			DDR_D4							
G4	—	DDR_D[3]			DDR_D3							
D4	—	DDR_D[2]			DDR_D2							
H3	—	DDR_D[1]			DDR_D1							
F4	—	DDR_D[0]			DDR_D0							
G2	—	DDR_DQM[1]			DDR_DQM1							
J4	—	DDR_DQM[0]			DDR_DQM0							
E1	—	DDR_DQS[1]			DDR_DQS1							
D3	—	DDR_DQS[0]			DDR_DQS0							
F1	—	DDR_DQS_b[1]			DDR_DQS_b1							
E3	—	DDR_DQS_b[0]			DDR_DQS_b0							
A4	—	DDR_RAS_b			DDR_RAS_b							
C6	—	DDR_WE_b			DDR_WE_b							
C4	—	DDR_ODT[0]			DDR_ODT0							
B1	—	DDR_ODT[1]			DDR_ODT1							
G5	—	DDR_VREF			DDR_VREF							
A3	—	DDR_ZQ			DDR_ZQ							
D6	—	DDR_RESET			DDR_RESET							
J20	—	PTD31		PTD31	FB_AD31	NF_IO15		FTM3_CH0	SPI2_PCS1			
H20	—	PTD30		PTD30	FB_AD30	NF_IO14		FTM3_CH1	SPI2_PCS0			
H18	—	PTD29		PTD29	FB_AD29	NF_IO13		FTM3_CH2	SPI2_SIN			
H17	—	PTD28		PTD28	FB_AD28	NF_IO12	I2C2_SCL	FTM3_CH3	SPI2_SOUT			
H16	—	PTD27		PTD27	FB_AD27	NF_IO11	I2C2_SDA	FTM3_CH4	SPI2_SCK			
G16	—	PTD26		PTD26	FB_AD26	NF_IO10		FTM3_CH5	SDHC1_WP			
G18	—	PTD25		PTD25	FB_AD25	NF_IO9		FTM3_CH6				
G19	—	PTD24		PTD24	FB_AD24	NF_IO8		FTM3_CH7				

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
G20	124	PTD23		PTD23/ MII0_ RXDATA[3]	FB_AD23	NF_IO7	FTM2CH0	ENET0_ 1588_TMR0	SDHC0_ DAT4	SCI2_TX	DCU1_R3	
F20	126	PTD22		PTD22/ MII0_ RXDATA[2]	FB_AD22	NF_IO6	FTM2CH1	ENET0_ 1588_TMR1	SDHC0_ DAT5	SCI2_RX	DCU1_R4	
F19	128	PTD21		PTD21/ MII0_CRS	FB_AD21	NF_IO5		ENET0_ 1588_TMR2	SDHC0_ DAT6	SCI2_RTS	DCU1_R5	
F17	129	PTD20		PTD20/ MII0_COL	FB_AD20	NF_IO4		ENET0_ 1588_TMR3	SDHC0_ DAT7	SCI2_CTS	DCU1_R0	
F16	130	PTD19		PTD19	FB_AD19	NF_IO3	ESAI_SCKR	I2C0_SCL	FTM2_QD_ PHA	MII0_ TXDATA[3]	DCU1_R1	
E18	131	PTD18		PTD18	FB_AD18	NF_IO2	ESAI_FSR	I2C0_SDA	FTM2_QD_ PHB	MII0_ TXDATA[2]	DCU1_G0	
E20	132	PTD17		PTD17	FB_AD17	NF_IO1	ESAI_HCKR	I2C1_SCL		MII0_TXERR	DCU1_G1	
D20	133	PTD16		PTD16	FB_AD16	NF_IO0	ESAI_HCKT	I2C1_SDA			DCU1_G2	
Y17	86	PTD0		PTD0	QSPI0_A_ SCK	SCI2_TX		FB_AD15	SPDIF_ EXTCLK			
Y18	87	PTD1		PTD1	QSPI0_A_ CS0	SCI2_RX		FB_AD14	SPDIF_IN1			
V18	88	PTD2		PTD2	QSPI0_A_ DATA3	SCI2_RTS	SPI1_PCS3	FB_AD13	SPDIF_OUT1			
Y19	89	PTD3		PTD3	QSPI0_A_ DATA2	SCI2_CTS	SPI1_PCS2	FB_AD12	SPDIF_ PLOCK			
W19	90	PTD4		PTD4	QSPI0_A_ DATA1		SPI1_PCS1	FB_AD11	SPDIF_ SRCLK			
W20	91	PTD5		PTD5	QSPI0_A_ DATA0		SPI1_PCS0	FB_AD10				
V20	92	PTD6		PTD6	QSPI0_A_ DQS		SPI1_SIN	FB_AD9				
V19	93	PTD7		PTD7	QSPI0_B_ SCK		SPI1_SOUT	FB_AD8				
U17	94	PTD8		PTD8	QSPI0_B_ CS0	FB_CLKOUT	SPI1_SCK	FB_AD7				
U18	97	PTD9		PTD9	QSPI0_B_ DATA3	SPI3_PCS1		FB_AD6		SAI1_TX_ SYNC	DCU1_B0	
U20	98	PTD10		PTD10	QSPI0_B_ DATA2	SPI3_PCS0		FB_AD5			DCU1_B1	
T20	99	PTD11		PTD11	QSPI0_B_ DATA1	SPI3_SIN		FB_AD4				
T19	100	PTD12		PTD12	QSPI0_B_ DATA0	SPI3_SOUT		FB_AD3				
T18	101	PTD13		PTD13	QSPI0_B_ DQS	SPI3_SCK		FB_AD2				
A19	141	PTB23		PTB23	SAI0_TX_ BCLK	SCI1_TX		FB_MUXED_ ALE	FB_TS_b	SCI3_RTS	DCU1_G3	

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
G14	—	VSS			VSS							
J14	—	VSS			VSS							
L14	—	VSS			VSS							
N14	—	VSS			VSS							
N7	—	FA_VDD			FA_VDD							
V14	—	VBAT			VBAT							
—	FLG	VSS			VSS							

12.2 Pinout diagrams

NOTE

The 176 LQFP parts are not pin compatible between the F and R series families devices.

NOTE

If tamper detection is not required, the tamper pins must be tied to ground.

Table 78. RGPIO versus Pins (continued)

RGPIO	In GPIO module	Corresponding Pin on the chip	IOMUX register name	IOMUX register address
RGPIO[40]	PORT1[8]	PTB18	IOMUXC_PTB18	400480A0
RGPIO[41]	PORT1[9]	PTB19	IOMUXC_PTB19	400480A4
RGPIO[42]	PORT1[10]	PTB20	IOMUXC_PTB20	400480A8
RGPIO[43]	PORT1[11]	PTB21	IOMUXC_PTB21	400480AC
RGPIO[44]	PORT1[12]	PTB22	IOMUXC_PTB22	400480B0
RGPIO[45]	PORT1[13]	PTC0	IOMUXC_PTC0	400480B4
RGPIO[46]	PORT1[14]	PTC1	IOMUXC_PTC1	400480B8
RGPIO[47]	PORT1[15]	PTC2	IOMUXC_PTC2	400480BC
RGPIO[48]	PORT1[16]	PTC3	IOMUXC_PTC3	400480C0
RGPIO[49]	PORT1[17]	PTC4	IOMUXC_PTC4	400480C4
RGPIO[50]	PORT1[18]	PTC5	IOMUXC_PTC5	400480C8
RGPIO[51]	PORT1[19]	PTC6	IOMUXC_PTC6	400480CC
RGPIO[52]	PORT1[20]	PTC7	IOMUXC_PTC7	400480D0
RGPIO[53]	PORT1[21]	PTC8	IOMUXC_PTC8	400480D4
RGPIO[54]	PORT1[22]	PTC9	IOMUXC_PTC9	400480D8
RGPIO[55]	PORT1[23]	PTC10	IOMUXC_PTC10	400480DC
RGPIO[56]	PORT1[24]	PTC11	IOMUXC_PTC11	400480E0
RGPIO[57]	PORT1[25]	PTC12	IOMUXC_PTC12	400480E4
RGPIO[58]	PORT1[26]	PTC13	IOMUXC_PTC13	400480E8
RGPIO[59]	PORT1[27]	PTC14	IOMUXC_PTC14	400480EC
RGPIO[60]	PORT1[28]	PTC15	IOMUXC_PTC15	400480F0
RGPIO[61]	PORT1[29]	PTC16	IOMUXC_PTC16	400480F4
RGPIO[62]	PORT1[30]	PTC17	IOMUXC_PTC17	400480F8
RGPIO[63]	PORT1[31]	PTD31	IOMUXC_PTD31	400480FC
RGPIO[64]	PORT2[0]	PTD30	IOMUXC_PTD30	40048100
RGPIO[65]	PORT2[1]	PTD29	IOMUXC_PTD29	40048104
RGPIO[66]	PORT2[2]	PTD28	IOMUXC_PTD28	40048108
RGPIO[67]	PORT2[3]	PTD27	IOMUXC_PTD27	4004810C
RGPIO[68]	PORT2[4]	PTD26	IOMUXC_PTD26	40048110
RGPIO[69]	PORT2[5]	PTD25	IOMUXC_PTD25	40048114
RGPIO[70]	PORT2[6]	PTD24	IOMUXC_PTD24	40048118
RGPIO[71]	PORT2[7]	PTD23	IOMUXC_PTD23	4004811C
RGPIO[72]	PORT2[8]	PTD22	IOMUXC_PTD22	40048120
RGPIO[73]	PORT2[9]	PTD21	IOMUXC_PTD21	40048124
RGPIO[74]	PORT2[10]	PTD20	IOMUXC_PTD20	40048128
RGPIO[75]	PORT2[11]	PTD19	IOMUXC_PTD19	4004812C
RGPIO[76]	PORT2[12]	PTD18	IOMUXC_PTD18	40048130
RGPIO[77]	PORT2[13]	PTD17	IOMUXC_PTD17	40048134
RGPIO[78]	PORT2[14]	PTD16	IOMUXC_PTD16	40048138

Table continues on the next page...

Table 81. Functional Assignment Pins (continued)

Signal Name	364 MAP BGA	176 LQFP (R-series ONLY)	Power Group	Pad Type	Default Mode (Reset)	Default Function	Input/ Output	Value
DDR_CLK_b[0]	B2	—	SDRAMC_VDD2P5	DDR	—	DDR_CLK_b[0]	—	—
DDR_CS_b[0]	C5	—	SDRAMC_VDD2P5	DDR	—	DDR_CS_b[0]	—	—
DDR_D[0]	F4	—	SDRAMC_VDD2P5	DDR	—	DDR_D[0]	—	—
DDR_D[1]	H3	—	SDRAMC_VDD2P5	DDR	—	DDR_D[1]	—	—
DDR_D[2]	D4	—	SDRAMC_VDD2P5	DDR	—	DDR_D[2]	—	—
DDR_D[3]	G4	—	SDRAMC_VDD2P5	DDR	—	DDR_D[3]	—	—
DDR_D[4]	F3	—	SDRAMC_VDD2P5	DDR	—	DDR_D[4]	—	—
DDR_D[5]	J3	—	SDRAMC_VDD2P5	DDR	—	DDR_D[5]	—	—
DDR_D[6]	C3	—	SDRAMC_VDD2P5	DDR	—	DDR_D[6]	—	—
DDR_D[7]	G3	—	SDRAMC_VDD2P5	DDR	—	DDR_D[7]	—	—
DDR_D[8]	J1	—	SDRAMC_VDD2P5	DDR	—	DDR_D[8]	—	—
DDR_D[9]	D1	—	SDRAMC_VDD2P5	DDR	—	DDR_D[9]	—	—
DDR_D[10]	H1	—	SDRAMC_VDD2P5	DDR	—	DDR_D[10]	—	—
DDR_D[11]	E2	—	SDRAMC_VDD2P5	DDR	—	DDR_D[11]	—	—
DDR_D[12]	G1	—	SDRAMC_VDD2P5	DDR	—	DDR_D[12]	—	—
DDR_D[13]	C1	—	SDRAMC_VDD2P5	DDR	—	DDR_D[13]	—	—
DDR_D[14]	H2	—	SDRAMC_VDD2P5	DDR	—	DDR_D[14]	—	—
DDR_D[15]	D2	—	SDRAMC_VDD2P5	DDR	—	DDR_D[15]	—	—
DDR_DQM[0]	J4	—	SDRAMC_VDD2P5	DDR	—	DDR_DQM[0]	—	—
DDR_DQM[1]	G2	—	SDRAMC_VDD2P5	DDR	—	DDR_DQM[1]	—	—
DDR_DQS[0]	D3	—	SDRAMC_VDD2P5	DDR	—	DDR_DQS[0]	—	—

Table continues on the next page...

Table 82. Revision History (continued)

Rev. No.	Date	Substantial Changes
		• Removed Temperature Voltage Monitor section to security RM • Updated VideoADC Specifications table
Rev 5	April 2013	Updated pin muxing table with the following changes: • Added MII0 including M AC0.TXDATA[2], MAC0.TXDATA[3], MAC0.RXDATA[2], MAC0.RXDATA[3] , MAC0.TXERR, MAC0.TXCLK, MAC0.RXCLK, MAC0.COL, MAC0.CRS • Following signals muxed on same RMII0 Pins : MII0_MDC, MII0_MDC, MII0_RXD[1], MII0_RXD[0], MII0_RXER, MII0_TXD[1], MII0_TXD[0], MII0_TXEN • Replaced FB_ALE with FB_MUXED_ALE, FB_CS4_b with FB_MUXED_TSIZ0, FB_TSIZ1 with FB_MUXED_TSIZ1, FB_TBST_b with FB_MUXED_TBST_b, FB_BE0_b with FB_MUXED_BE0_b • Removed RCON18,19,20 • Replaced ESAI_SDO2 with ESAI_SDO2/ESAI_SDI3 Replaced ESAI_SDO3 with ESAI_SDO3/ ESAI_SDI2 Replaced ESAI_SDI0 with ESAI_SDO5/ESAI_SDI0 Replaced ESAI_SDI1 with ESAU_SDO4/ESAI_SDI1 • CKO1 additionally muxed at PAD40
Rev 5	May 2013	In the Features, minor editorial updates Added Part Number Format figure Updated the Fields table as per the device part numbers Added Part Numbers table Added External NPN Ballast section In the LVD Dig Electrical Specs, minimum value of Upper Voltage Threshold and Lower Voltage threshold In the FlexBus timing specifications table, clarified the Frequency of operation In the Power consumption, filled TBDs. Updated footnotes

Table continues on the next page...

Table 82. Revision History

Rev. No.	Date	Substantial Changes
		supply), turn this 1.5 V supply on before turning on the 3.3V." • In "VideoADC specifications" table, added supply current values. • In "Receive and Transmit signal timing specifications," added the following note: "See the most current errata document when using the internally generated RXCLK and TXCLK clocks." • Updated "QuadSPI timing" section, presenting data based on a negative edge data launch from the device and a negative edge data capture; updated the figure, "QuadSPI Input/Read timing (SDR mode)"; updated the table, "QuadSPI Input/Read timing (SDR mode)." • For the "SDHC switching specifcations" table, added the statement, "A load of 50 pF is assumed"; updated max value for SD6, SDHC output delay (output valid). • In the "24 MHz oscillator specifications" section, added the statement, "The crystal must be rated for a drive level of 250 µW or higher. An ESR (equivalent series resistance) of 80 Ω or less is recommended to achieve a gain margin of 5." • In "Pinouts" section, for the 176LQFP package, added information about exposed pad on the bottom side. • In "Special Signal Considerations" table, added that a "fundamental-mode" crystal should be connected between XTAL and EXTAL; updated maximum drive level of crystal rating to 250 µW.